



LATW2007

8th IEEE Latin-American Test Workshop



March 11-14, 2007
Cuzco, Peru

www.latw.net

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Call for Papers

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The IEEE Latin American Test Workshop provides an annual forum for test and fault tolerance professionals and technologists from Latin America and all over the world to present and discuss various aspects of system, board and component testing and fault-tolerance with design, manufacturing and field considerations in mind. The best papers presented at the 8th LATW will be invited for submission to the IEEE Design and Test of Computers and Journal of Integrated Circuits and Systems.

Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Board and System Test
- Built-In Self-Test
- Defect-Based Test
- Dependability
- Design and Synthesis for Testability
- Design Verification/Validation
- Design for Manufacturability
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation Hardening Techniques
- System-on-Chip Test
- Yield Optimization

Topic Coordinators:

Analog and Mixed-Signal - M. Renovell, LIRMM, France
DFT & BIST - A. Orailoglu, UC San Diego, USA
On-line Test and Fault Tolerance - D. K. Pradhan, University of Bristol, UK
Space Radiation - F. Lima, UFRGS, Brazil
Verification and High Level Test - M. Reorda, Politecnico di Torino, Italy
Software Testing - E. Bezerra, PUCRS, Brazil

Paper Submission Information:

To encourage and facilitate informal discussion, participation will be limited. Those interested in presenting recent results at the workshop are invited to submit either an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions **should be done via the workshop webpage: www.latw.net**. Authors should send papers in the IEEE format with a cover letter indicating the complete mail address, phone/fax numbers and e-mail addresses, the contact person and the presenter. Detailed instructions are available at the workshop webpage. The Program Committee also welcomes proposals for panels and special topic sessions. For additional information please contact one of the Program Co-Chairs.

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Submission deadline: December 3th, 2006

Notification of acceptance: January 14th, 2007

Camera Ready: January 26th, 2007

LATW2007 will be held in Cuzco, Peru. The city of Cusco is located at the central and south-eastern zone of Peru. Cusco, was the mythical capital of the Inca Empire. You'll find the amazing artistic legacy from the Incas such as huge temples, palaces and artefacts. Cusco offers beautiful landscapes and an approach to the ancient Inca culture. There you also can find many structures built during the Spanish colony, that evoke the greatness of the Children of the Sun and the Spanish influence after the conquest. Cusco Capital of Andean Culture offers magnificent expressions of Pre-Columbian and Colonial Art. Nowadays Cusco artisans still preserve techniques from this period, mixed with knowledge from the Spanish influence. Colours, friendship, pleasure and a great diversity of customs and traditions, handicrafts and folklore dances.

Sponsored by: IEEE Computer Society Test Technology Technical Council (TTTC)

Organized by: Pontificia Universidad Catolica del Peru (PUCP)

National Institute for Astrophysics, Optics and Electronics, INAOE

